

Search Notes**Application/Control No.**

10/765,276

Examiner

Vuthe Siek

Applicant(s)/Patent under Reexamination

TAKEOKA ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	4-6	2/22/2006	VS
702	58,59	5/8/2006	VS
702	117-119	5/8/2006	VS
702	185,189	5/8/2006	VS
324	238,500	5/8/2006	VS
324	512,527	5/8/2006	VS
714	700,744	5/8/2006	VS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST ALL DATABASES & IEEE (SEE SEARCH HISTORY PRINTOUTS)	2/22/2006	VS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner